


<b>Search Notes</b>  	<b>Application/Control No.</b>  10645352	<b>Applicant(s)/Patent Under Reexamination</b>  RYPAN, ZENON
	<b>Examiner</b>  Philip H Leung	<b>Art Unit</b>  3742

SEARCHED			
Class	Subclass	Date	Examiner
219	756-757, 745-746, 754, 680	updated	P.L.
312	236	2-18-2008	
126	37R		
D7	351		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner